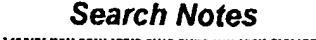


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/766,374	CHEN, SHAU-LIN F.
	Examiner	Art Unit
	Wayne Langel	1754

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
423	239.1	1-5-05	WAL
423	244.02	1-5-05	WAL